- Design to Protect Submicron 3-V or 5-V Silicon from Noise Transients
- Applicable to Two High- or Low-Speed Universal Serial Bus (USB) Host, Hub or Peripheral Ports
- Port ESD Protection Capability Exceeds:
  - 15-kV Human Body Model
  - 2-kV Machine Model
  - 8-kV IEC1000-4-2<sup>†</sup>
- Low Current Leakage . . . 1 μA Max
- Stand-Off Voltage . . . 6.0 V Min
- Low Capacitance . . . 35 pF Typ

## description

The SN75240 is four transient voltage suppressors designed to provide additional electrical noise transient protection to two USB ports. Any cabled I/O can be subjected to electrical noise transients from various sources. These noise transients can cause damage to the USB transceiver and/or the USB ASIC if they are of sufficient magnitude and duration. The USB ports are typically implemented in 3-V or 5-V digital CMOS with very limited ESD protection. The SN75240 can significantly increase the port ESD protection level and reduce the risk of damage to the large and expensive circuits of the USB port.

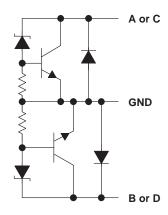
### IEC1000-4-2 Compliance Test Levels

IEC1000-4-2 COMPLIANCE LEVEL	MAXIMUM TEST VOLTAGE		
	CONTACT DISCHARGE (kV)	AIR DISCHARGE (kV)	
1	2	2	
2	4	4	
3	6	8	
4	8	15	

### P OR PW PACKAGE (TOP VIEW)

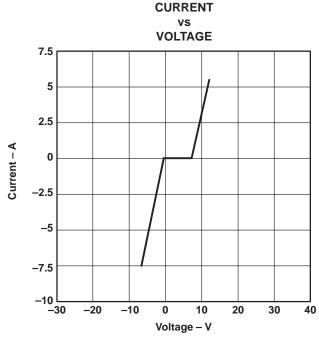


### schematic



(One Suppressor Shown)

NOTE A: All four GND terminals should be connected to ground.



NOTE A: Typical current versus voltage curve was derived using the IEC 1.2/50-µs surge waveform.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

† IEC1000-4-2 ESD performance is measured at the systems level and system designs influence the results of these tests. Testing done at the component level act as an indicator that the system passes at a particular compliance level, but does not ensure that the system passes at that level. The Texas Instruments USB EVM with the TUSB2040 USB controller (2-kV HBM and 200-V MM) was used for the test platform.

TEXAS INSTRUMENTS

# absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Continuous total power dissipation	See Dissipation Rating Table
Electrostatic discharge	Class 3, A:15 kV, B: 2 kV
Peak power dissipation, P <sub>D(peak)</sub>	60 W
Peak forward surge current, I <sub>FSM</sub>	3 A
Peak reverse surge current, I <sub>RSM</sub>	
Storage temperature range, T <sub>stq</sub>	65°C to 150°C
Lead temperature 1.6 mm (1/16 inch) from case for 10 seconds	3

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### **DISSIPATION RATING TABLE**

PACKAGE	$T_{\mbox{\scriptsize A}} \leq 25^{\circ}\mbox{\scriptsize C}$ POWER RATING	DERATING FACTOR ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 70°C POWER RATING	T <sub>A</sub> = 85°C POWER RATING
Р	1150 mW	9.2 mW/°C	736 mW	598 mW
PW	520 mW	4.2 mW/°C	331 mW	268 mW

<sup>‡</sup>This is the inverse of the junction-to-ambient thermal resistance when board-mounted and with no air flow.

## recommended operating conditions

	MIN	MAX	UNIT
Operating free-air temperature, T <sub>A</sub>	0	70	°C

# electrical characteristics over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
l <sub>lkg</sub>	Leakage current	V <sub>I</sub> = 6 V at A, B, C, or D terminals			1	μΑ
V(BR)	Breakdown voltage	V <sub>I</sub> = 1 mA at A, B, C, or D terminals		7		V

## **APPLICATION INFORMATION**

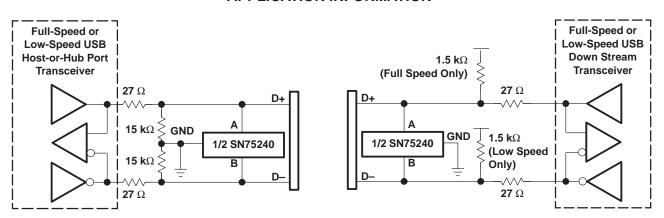


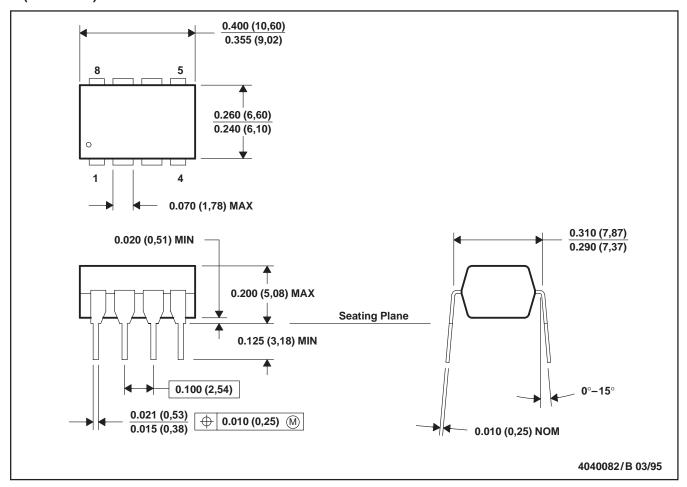
Figure 1. Typical USB Application



# **MECHANICAL INFORMATION**

## P (R-PDIP-T8)

### PLASTIC DUAL-IN-LINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

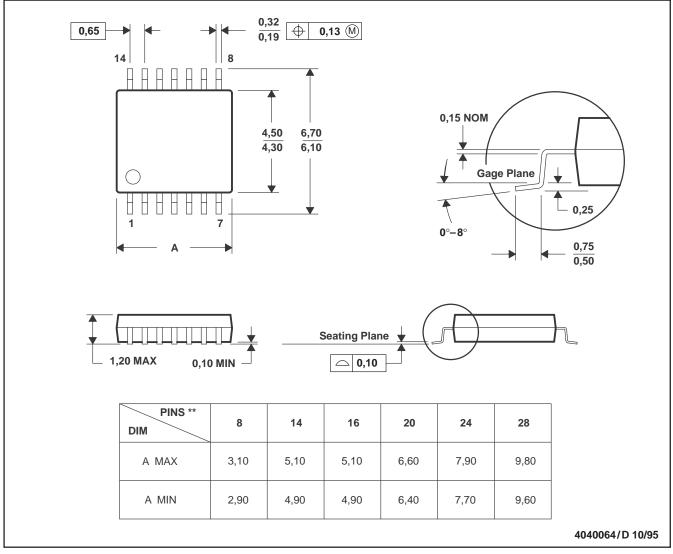
- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MS-001

## **MECHANICAL INFORMATION**

# PW (R-PDSO-G\*\*)

## PLASTIC SMALL-OUTLINE PACKAGE

## 14 PIN SHOWN



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.
- D. Falls within JEDEC MO-153



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